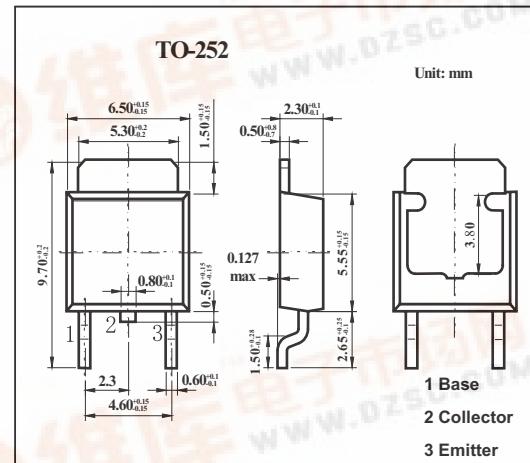


SMD Type

Transistors

NPN Silicon Epitaxial Transistor

2SC2946



■ Features

- High Voltage V_{CBO}=200V
- High speed t_f< μ s

■ Absolute Maximum Ratings Ta = 25°C

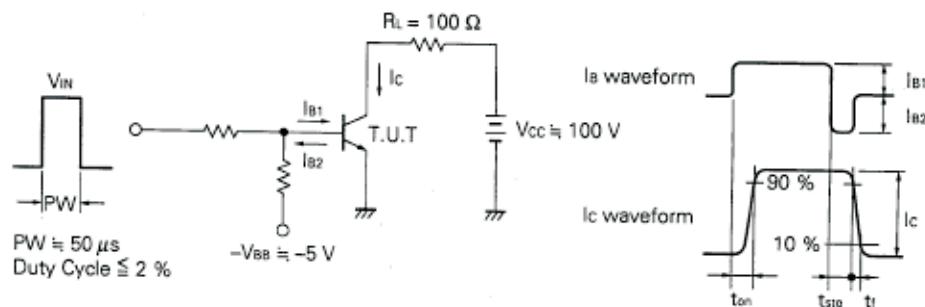
Parameter	Symbol	Rating	Unit
Collector to base voltage	V _{CBO}	330	V
Collector to emitter voltage	V _{CEO}	200	V
Emitter to base voltage	V _{EBO}	7	V
Collector current	I _{CP}	2	A
Collector peak current *1	I _C	4	A
Total Power dissipation Ta = 25°C *2	P _T	2	W
Junction temperature	T _j	150	°C
Storage temperature	T _{stg}	-55 to +150	°C

*1 PW ≤ 10ms, Duty cycle ≤ 50%

*2 when mounted on ceramic substrate of 7.5cm² × 0.7mm

2SC2946■ Electrical Characteristics $T_a = 25^\circ\text{C}$

Parameter	Symbol	Testconditons	Min	Typ	Max	Unit
collector cutoff current	I_{CBO}	$V_{CB}=250\text{V}, I_E=0$			1	μA
emitter cutoff current	I_{EBO}	$V_{EB}=5\text{V}, I_C=0$			1	μA
DC current Gain *	h_{FE}	$V_{CE}=5\text{V}, I_C=100\text{mA}$	20	60	160	
		$V_{CE}=5\text{V}, I_C=1\text{A}$	15			
Collector Saturation Voltage *	$V_{CE(\text{sat})}$	$I_C=1\text{A}, I_B=0.1\text{A}$			1	V
Base Saturation Voltage *	$V_{BE(\text{sat})}$	$I_C=1\text{A}, I_B=0.1\text{A}$			1.5	V
Turn-on Time	t_{on}	see Test circuit			1	μs
Storage Time	t_{stg}				2	
Fall Time	t_f				1	

* Pulsed: $PW \leq 350\mu\text{s}$, Duty Cycle $\leq 2\%$ ■ Switching Time(t_{on}, t_{stg}, t_f) Test Circuit

■ hFE Classification

Marking	N	M	L	K
hFE	20 to 50	30 to 70	50 to 100	80 to 160